


| FORM PTO-1449 | |  | | Atty. Docket No. SEN-020 | Serial No. 10/081,078 | |
|--|--------------------|---|----------|-------------------------------------|--------------------------|-----------------------|
| LIST OF PRIOR ART CITED BY APPLICANT | | | | Applicant: Adam E. Norton et al. | | |
| | | | | Filing Date: February 21, 2002 | Group# 2877 2872 | |
| U.S. PATENT DOCUMENTS | | | | | | |
| Examiner Initial* | Document Number | Grant Date | Name | Class | Sub Class | Filing Date |
| CXC | AA | 4,572,608 | 02/25/86 | Mochizuki et al. | 350 | 96.15 |
| CXC | AB | 4,922,309 | 05/01/90 | Sekiwa et al. | 356 | 300 |
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| Examiner Initial* | Document Number | Grant Date | Country | Class | Sub Class | Translation Yes No |
| | AK | | | | | |
| | AL | | | | | |
| OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.) | | | | | | |
| CXC | AM | M.E. Lee et al., "Analysis of Reflectometry and Ellipsometry Data from Patterned Structures", Dept. of Electrical Engineering and Computer Science, Univ. of Michigan, MI, 5 pages. | | | | |
| EXC | AN | Nasa Research Announcement, "Technical Details on OMI and Other EOS Chem Instruments", Sept. 29, 1999, 2 pages. | | | | |
| CXC | AO | Varian Inc. paper, Scientific Instruments, "Polarizer and Depolarizer Accessory", June 28, 2000, 2 pages. | | | | |
| EXAMINER: | | | | DATE CONSIDERED: | | |
| Craig H. Curtis | | | | 5 December '03 | | |
| *Examiner: Initial/If citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. | | | | | | |

U.S. PATENT DOCUMENTSFOREIGN PATENT DOCUMENTS

OTHER DOCUMENTS

(Including Author, Title, Date, Pertinent Pages, Etc.)

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|---|------------------------|-----------------|------------------------|
| Examiner | <i>Craig S. Curtis</i> | Date Considered | <i>5 December 2003</i> |
| Examiner: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. | | | |

Modified Form PTO-A820
(also form PTO-1449)

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